DIGITRON™
Semiconductors

High-reliability discrete products
and engineering services since 1977

HR FLOW

RECTIFIER DIODES

All parts are screened per MIL-PRF-19500, JANTX Level and the device detail specification. All testing is performed at room temperature, unless indicated otherwise. For testing at high and low temperatures, Group A testing is required.

	Test	**Method**	**Conditions / Notes**
1	**Temperature Cycling**	*MIL-STD-750 Method 1051*	Test condition C or maximum storage temperature, whichever less. 20 cycles, 10 minutes per extreme.
2	**Surge Test**	*MIL-STD-750 Method 4066*	Rated I_{FSM} as specified in the detail drawing.
3	**Thermal Impedance**	*MIL-STD-750 Method 3101*	As specified in the detail drawing.
4	**High Temperature Reverse Bias Burn-in (HTRB)**	*MIL-STD-750 Method 1038*	Condition A. 80% of rated V_R for 48 hours at 150°C.
5	**Interim Electrical Testing**		DC parameters per device detail specification.
6	**Power Burn-in**	*MIL-STD-750 Method 1038*	96 hours of forward bias per device detail specification.
7	**Final Electrical Testing**		DC parameters per device detail specification.
8	**Delta Calculation**		Delta parameters and limits per device detail specification.
9	**PDA Calculation**		10 percent defective allowed.
10	**Seal Test Gross Leak**	*MIL-STD-750 Method 1071*	Condition C

Notes:

1. Testing varies in accordance with the device detail specification.
2. Specific customer testing needs may be accommodated into any testing flow (selection tests, temperature requirements, special tests).

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